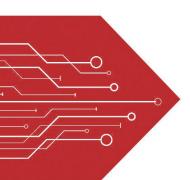
MSKSEMI















ESD

TVS

TSS

MOV

GDT

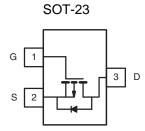
PLED

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Features

- $-20V, -3A, RDS(ON) = 70m\Omega@VGS = -4.5V$
- Improved dv/dt capability
- Fast switching
- Green Device Available

Applications

- Notebook
- Load Switch
- Battery Protection
- Hand-held Instruments

BVDSS	RDSON	ID
-20V	70m Ω	-3A

Absolute Maximum Ratings Tc=25°C unless otherwise noted

Symbol	Parameter	Rating	Units
V _{DS}	Drain-Source Voltage	-20	V
/ _{GS}	Gate-Source Voltage	±12	V
	Drain Current – Continuous (T _C =25°C)	-3.0	А
D	Drain Current – Continuous (T _C =100°C)	-2.1	А
DM	Drain Current – Pulsed ¹	-13	А
2	Power Dissipation (T _C =25°C)	1.56	W
D D	Power Dissipation – Derate above 25°C	0.012	W/°C
Г _{STG}	Storage Temperature Range	-55 to 150	°C
Γ _J	Operating Junction Temperature Range	-55 to 150	°C

Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Unit
$R_{\theta JA}$	Thermal Resistance Junction to ambient		80	°C/W







Electrical Characteristics (T_J=25 °C, unless otherwise noted)

Off Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =-250uA	-20		-	V
$\triangle BV_{DSS}/\triangle T_{J}$	BV _{DSS} Temperature Coefficient	Reference to 25°C , I _D =-1mA		-0.01		V/°C
	Dunin Course Lookens Courset	V _{DS} =-20V , V _{GS} =0V , T _J =25°C			-1	uA
I _{DSS}	Drain-Source Leakage Current	V _{DS} =-16V , V _{GS} =0V , T _J =125°C			-10	uA
I _{GSS}	Gate-Source Leakage Current	V _{GS} =±12V , V _{DS} =0V			±10	uA

On Characteristics

R _{DS(ON)} Static Drain-Source On-Resistance		V _{GS} =-4.5V , I _D =-3A		70	85	mΩ
		V _{GS} =-2.5V , I _D =-2A		95	120	11152
$V_{GS(th)}$	Gate Threshold Voltage	V _{GS} =V _{DS} , I _D =-250uA	-0.3	-0.65	-1.1	V
$\triangle V_{GS(th)}$	V _{GS(th)} Temperature Coefficient	V _{GS} -V _{DS} , I _D 250UA		3		mV/°C
gfs	Forward Transconductance	V _{DS} =-10V , I _S =-1A		2.2		S

Dynamic and switching Characteristics

Qg	Total Gate Charge ^{2, 3}		 4.8	
Q_{gs}	Gate-Source Charge ^{2, 3}	V_{DS} =-10V , V_{GS} =-4.5V , I_{D} =-3A	 0.5	 nC
Q_{gd}	Gate-Drain Charge ^{2, 3}		 1.9	
T _{d(on)}	Turn-On Delay Time ^{2 , 3}		 3.5	
T _r	Rise Time ^{2 , 3}	V_{DD} =-10V , V_{GS} =-4.5V , R_{G} =25 Ω	 12.6	 ~C
$T_{d(off)}$	Turn-Off Delay Time ^{2, 3}	I _D =-1A	 32.6	 nS
T _f	Fall Time ^{2, 3}		 8.4	
C _{iss}	Input Capacitance		 550	
C _{oss}	Output Capacitance	V _{DS} =-10V , V _{GS} =0V , F=1MHz	 65	 pF
C _{rss}	Reverse Transfer Capacitance		 55	

Drain-So						
Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source Current	\/ =\/ =0\/ Force Current			-3.0	Α
I _{SM}	Pulsed Source Current	V _G =V _D =0V , Force Current			-13	Α
V_{SD}	Diode Forward Voltage	V _{GS} =0V , I _S =-1A , T _J =25°C			-1.2	٧

Note:

- Repetitive Rating: Pulsed width limited by maximum junction temperature.
- The data tested by pulsed , pulse width \leq 300us , duty cycle \leq 2%.
- Essentially independent of operating temperature.

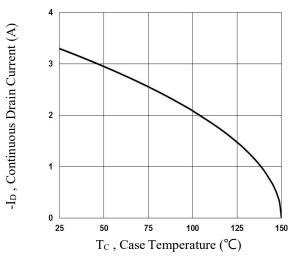


Fig.1 Continuous Drain Current vs. Tc

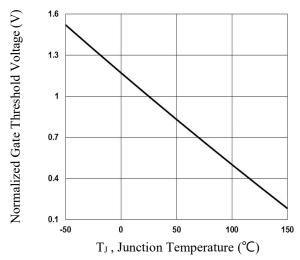


Fig.3 Normalized V_{th} vs. T_J

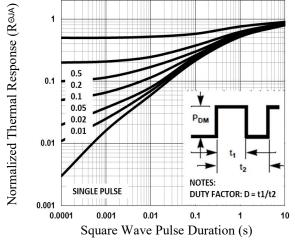


Fig.5 Normalized Transient Response

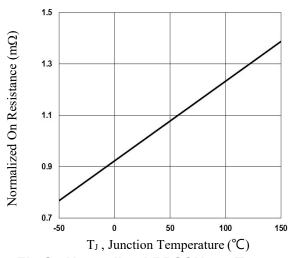


Fig.2 Normalized RDSON vs. TJ

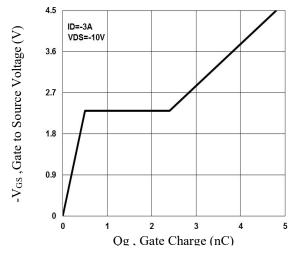


Fig.4 Gate Charge Waveform

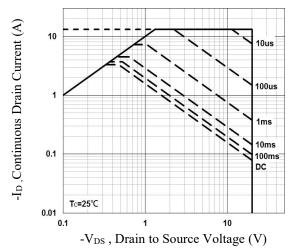
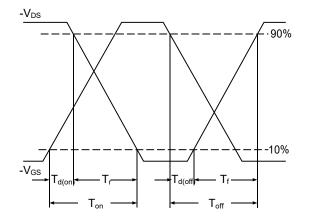


Fig.6 Maximum Safe Operation Area

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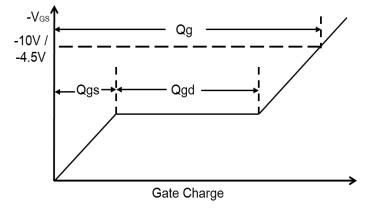


Fig.7 Switching Time Waveform

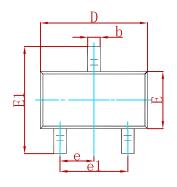
Fig.8 Gate Charge Waveform

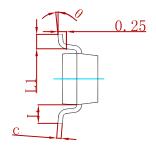


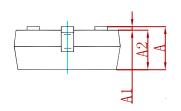




PACKAGE MECHANICAL DATA

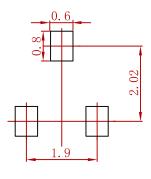






Symbol	Dimensions	Dimensions In Millimeters		s In Inches
Symbol	Min	Max	Min	Max
Α	0.900	1.150	0.035	0.045
A1	0.000	0.100	0.000	0.004
A2	0.900	1.050	0.035	0.041
b	0.300	0.500	0.012	0.020
С	0.080	0.150	0.003	0.006
D	2.800	3.000	0.110	0.118
Е	1.200	1.400	0.047	0.055
E1	2.250	2.550	0.089	0.100
е	0.950) TYP	0.037	7 TYP
e1	1.800	2.000	0.071	0.079
L	0.550	0.550 REF 0.022 RE		REF
L1	0.300	0.500	0.012	0.020
θ	0°	8°	0°	8°

Suggested Pad Layout



- 1.Controlling dimension:in millimeters. 2.General tolerance:± 0.05mm.
- 3. The pad layout is for reference purposes only.

REEL SPECIFICATION

P/N	PKG	QTY
SI2301CDS-T1-GE3-MS	SOT-23	3000

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